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### FAIRCHILD

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### FDB8870

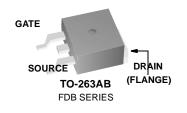
## N-Channel PowerTrench<sup>®</sup> MOSFET 30V, 160A, 3.9m $\Omega$

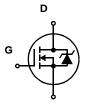
### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $r_{\text{DS}(\text{ON})}$  and fast switching speed.

### Applications

DC/DC converters





• High power and current handling capability

•  $r_{DS(ON)} = 3.9 m\Omega$ ,  $V_{GS} = 10V$ ,  $I_D = 35A$ 

•  $r_{DS(ON)} = 4.4m\Omega$ ,  $V_{GS} = 4.5V$ ,  $I_D = 35A$ 

· High performance trench technology for extremely low

**Features** 

r<sub>DS(ON)</sub>

· Low gate charge

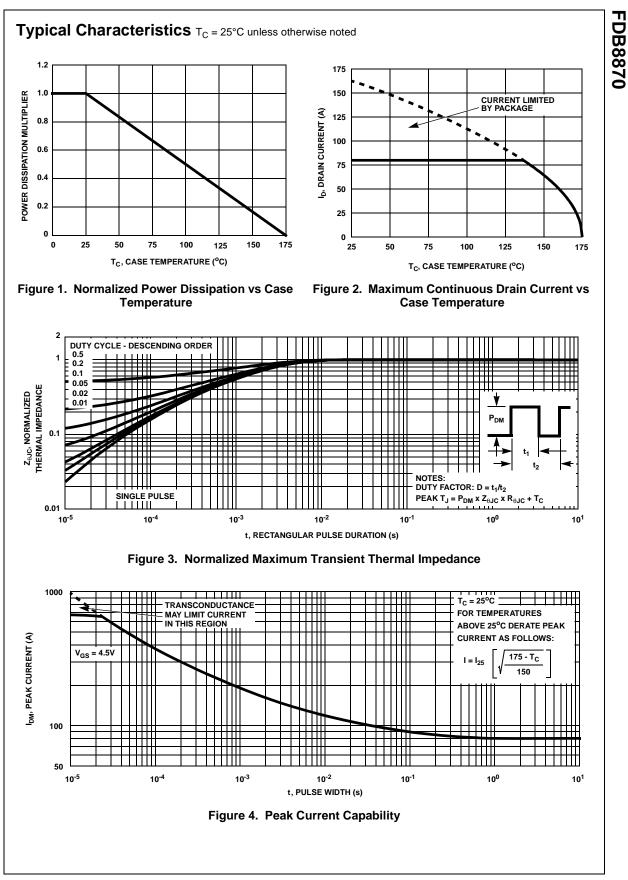
### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol V <sub>DSS</sub> V <sub>GS</sub>	Drain to Sou Gate to Sou	urce Voltage	rameter		Ratings 30	Units V	
		irce voltage					
V <sub>GS</sub>	Gate to Sou						
		rce Voltage	±20	V			
	Drain Currer	∩t					
	Continuous	$(T_{C} = 25^{\circ}C, V_{GS} = 10)$	160	A			
I <sub>D</sub>	Continuous	$(T_{C} = 25^{\circ}C, V_{GS} = 4)$	150	A			
	Continuous	$(T_{amb} = 25^{\circ}C, V_{GS} =$	23	A			
	Pulsed		Figure 4	A			
E <sub>AS</sub>	Single Pulse	e Avalanche Energy (	300	mJ			
П	Power dissip	oation	160	W			
P <sub>D</sub>	Derate abov	′e 25°C	1.07	W/ºC			
T <sub>J</sub> , T <sub>STG</sub>	Operating a	nd Storage Temperat	ture	-55 to 175	°C		
Thermal <sub>R<sub>θJC</sub></sub>	Charact	sistance Junction to	Case TO-263		0.94	°C/W	
R <sub>θJA</sub>	Thermal Re	sistance Junction to	62	°C/W			
$R_{ hetaJA}$	Thermal Res	sistance Junction to	43	°C/W			
		g and Orderin	ng Informatio	n Reel Size	Tape Width	Quantity	
Device M	arkind					800 units	

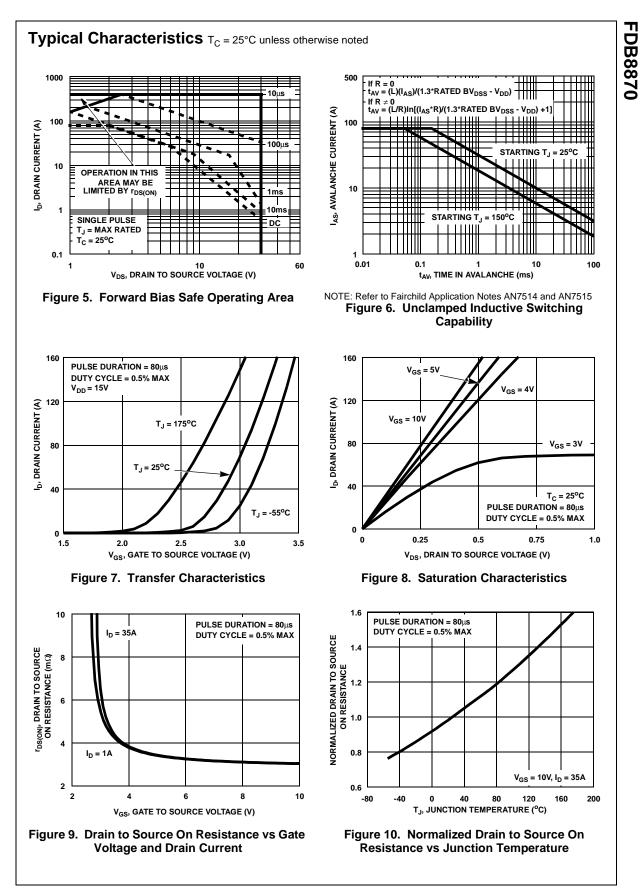
May 2008

# FDB8870

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
Off Chara	acteristics						
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	30	-	-	V	
I <sub>DSS</sub>		$V_{DS} = 24V$	-	-	1		
	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μA	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA	
	acteristics						
V <sub>GS(TH)</sub>	Gate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA	1.2	-	2.5	V	
· GS(IH)		$I_D = 35A, V_{GS} = 10V$	-	0.0032	0.0039		
r <sub>DS(ON)</sub>		$I_D = 35A, V_{GS} = 4.5V$	-	0.0038	0.0044	1	
	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$ 0.0051				Ω	
		$T_{\rm J} = 175^{\circ}{\rm C}$	-	- 0.0051 0.00	0.0065	5	
Dvnamic	Characteristics						
C <sub>ISS</sub>	Input Capacitance		-	5200	-	pF	
C <sub>OSS</sub>	Output Capacitance	$-V_{DS} = 15V, V_{GS} = 0V,$	-	970	-	, pF	
C <sub>RSS</sub>	Reverse Transfer Capacitance	f = 1MHz	-	570	-	pF	
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 0.5V, f = 1MHz	-	2.1	-	Ω	
Q <sub>g(TOT)</sub>	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$	-	106	132	nC	
$Q_{g(5)}$	Total Gate Charge at 5V	$V_{CS} = 0V$ to 5V	-	56	69	nC	
Q <sub>g(TH)</sub>	Threshold Gate Charge	$\frac{V_{GS} = 0V \text{ to } 1V}{I_D = 35A}$	-	5.0	6.5	nC	
Q <sub>gs</sub>	Gate to Source Gate Charge	$I_D = 35A$	-	15	-	nC	
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	I <sub>g</sub> = 1.0mA	-	10	-	nC	
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	-	-	23	-	nC	
	g Characteristics (V <sub>GS</sub> = 10V)						
t <sub>ON</sub>	Turn-On Time		-	-	162	ns	
t <sub>d(ON)</sub>	Turn-On Delay Time	-	-	10	-	ns	
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15V, I <sub>D</sub> = 35A	-	98	-	ns	
t <sub>d(OFF)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 3.3\Omega$	-	75	-	ns	
t <sub>f</sub>	Fall Time		-	47	-	ns	
t <sub>OFF</sub>	Turn-Off Time	-	-	-	183	ns	
	urce Diode Characteristics			1			
V <sub>SD</sub>		I <sub>SD</sub> = 35A	-	-	1.25	V	
	Source to Drain Diode Voltage	I <sub>SD</sub> = 15A	-	-	1.0	V	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 35A, dI <sub>SD</sub> /dt = 100A/μs	-	-	37	ns	
	Reverse Recovered Charge	I <sub>SD</sub> = 35A, dI <sub>SD</sub> /dt = 100A/µs	-	-	21	nC	

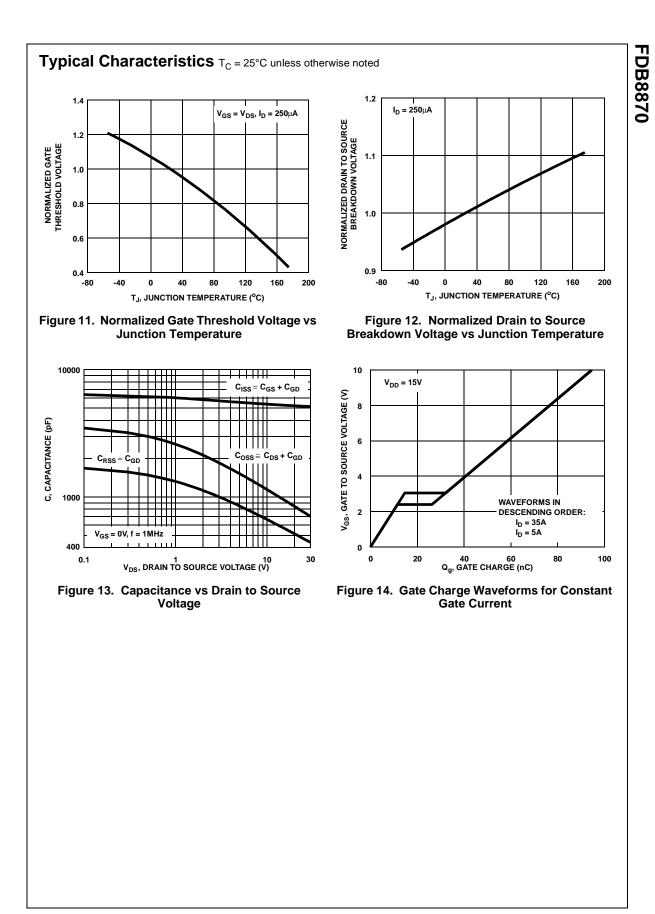


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### **Test Circuits and Waveforms**

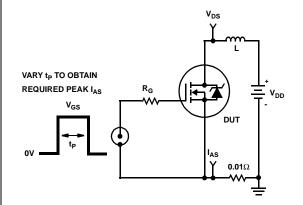


Figure 16. Unclamped Energy Waveforms



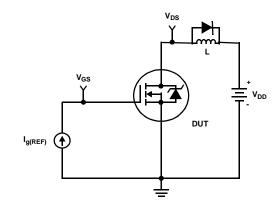


Figure 17. Gate Charge Test Circuit

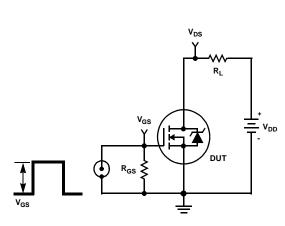


Figure 19. Switching Time Test Circuit

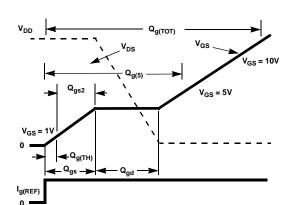
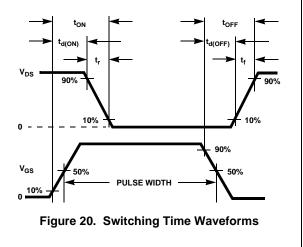


Figure 18. Gate Charge Waveforms



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### Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A$  (°C), and thermal resistance  $R_{\theta JA}$  (°C/W) must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of  $P_{DM}$  is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the  $R_{\theta,JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

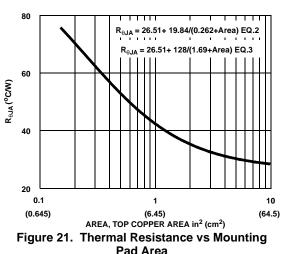
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

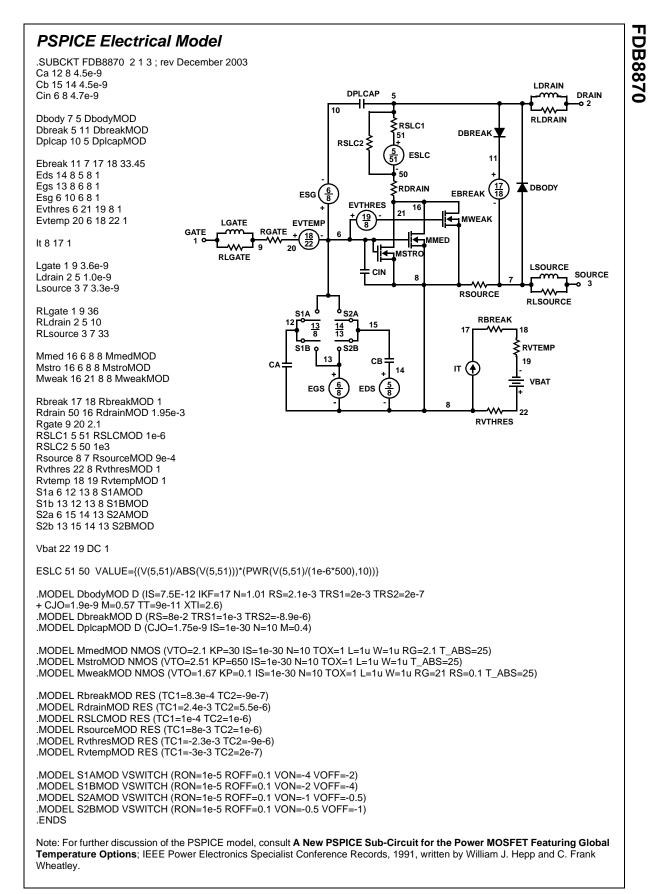
$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

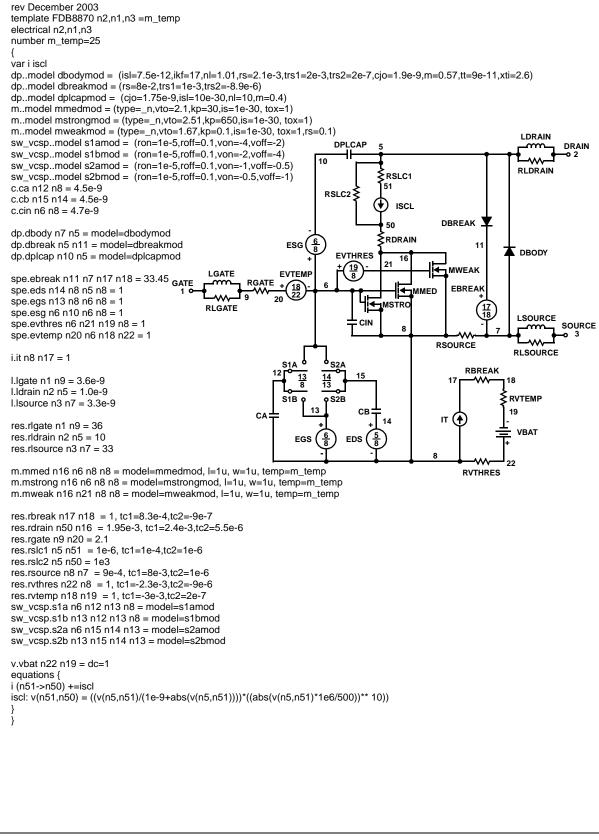
$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
(EQ. 3)

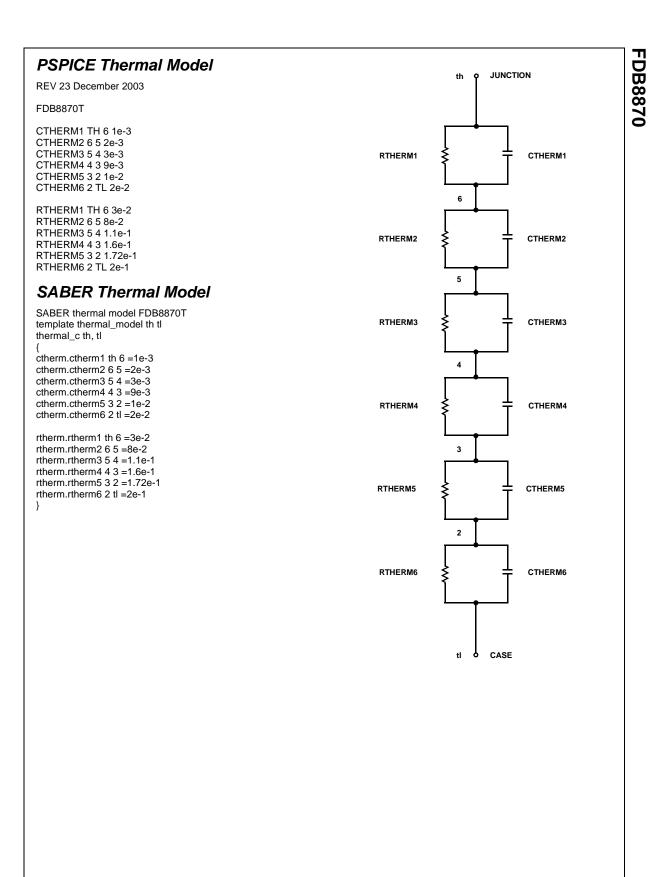
Area in Centimeters Squared





### SABER Electrical Model





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